

CMPA801B030D1

8 – 11 GHz, 40 W GaN HPA

Description

Wolfspeed’s CMPA801B030D1 is a 40W MMIC HPA utilizing Wolfspeed’s high performance, 0.15um GaN on SiC production process. The CMPA801B030D1 operates from 8-11 GHz and supports both defense and commercial-related radar applications. The CMPA801B030D1 achieves 40 W of saturated output power with 20 dB of large signal gain and typically 40% power-added efficiency under pulsed operation. CW operation is also an option.

The CMPA801B030D1 provides improved RF performance over previous generations allowing customers to improve SWaP-C benchmarks in their next-generation systems.



Figure 1. CMPA801B030D1

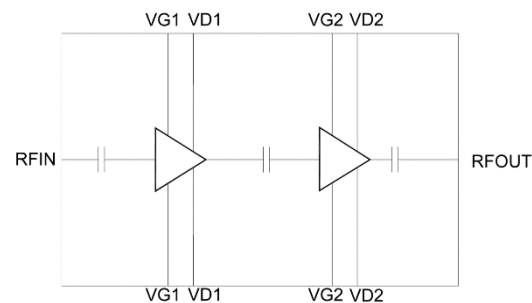


Figure 2. Functional Block Diagram

Features

- Psat: 40 W
- PAE: 40 %
- LSG: 20 dB
- S21: 27 dB
- S11: -10 dB
- S22: -6 dB
- Pulsed / CW operation

Note: Features are typical performance across frequency under 25C operation. Please reference performance charts for additional information.

Applications

- Military and Commercial Radar



Absolute Maximum Ratings

Parameter	Symbol	Units	Value	Conditions
Drain Voltage	V_d	V	28	
Gate Voltage	V_g	V	-10, +2	
Drain Current	I_d	A	4	
Gate Current	I_g	mA	12.9	
Input Power	P_{in}	dBm	29	
Dissipated Power	P_{diss}	W	98	85 °C
Storage Temperature	T_{stg}	°C	-55, +150	
Mounting Temperature	T_J	°C	260	30 seconds
Junction Temperature	T_J	°C	225	MTTF > 1E6
Output Mismatch Stress	VSWR	Ψ	5:1	

Recommended Operating Conditions

Parameter	Symbol	Units	Typical Value	Conditions
Drain Voltage	V_d	V	28	
Gate Voltage	V_g	V	-1.8	
Drain Current	I_{dq}	mA	800	
Input Power	P_{in}	dBm	26	
Case Temperature	T_{case}	°C	-40 to 85	

RF Specifications

Test conditions unless otherwise noted: $V_d=28V$, $I_{dq}=800mA$, $PW=100\mu s$, $DC=10\%$, $T_{base}=25\text{ }^\circ\text{C}$

Parameter	Units	Frequency	Min	Typical	Max	Conditions
Frequency	GHz		8		11	
Output Power	dBm	8		45.5		Pin = 26 dBm
		10		46.5		
		11		46.5		
Power-added Efficiency	%	8		40		Pin = 26 dBm
		10		39		
		11		36		
LSG	dB	8		19.5		Pin = 26 dBm
		10		20.5		
		11		20.5		
Small-Signal Gain (S21)	dB	8		28.5		
		10		26		
		11		25		
Input Return Loss	dB			-10		
Output Return Loss	dB			-6		

Test conditions unless otherwise noted: $V_d=28V$, $I_{dq}=800mA$, $PW=100\mu s$, $DC=10\%$, $P_{in}=26dBm$, $T_{base}=25^\circ C$, Frequency =9.5 GHz

Figure 3: Pout v. Frequency v. Temperature

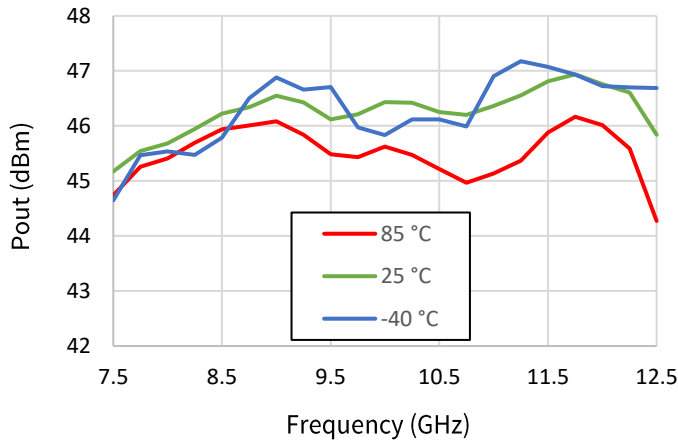


Figure 4: PAE v. Frequency v. Temperature

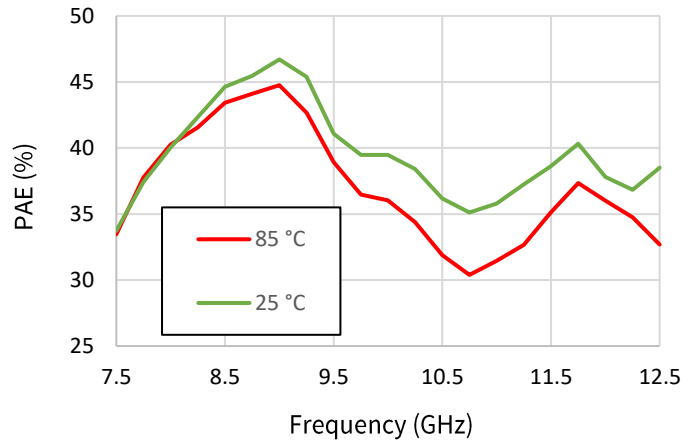


Figure 5: Id v. Frequency v. Temperature

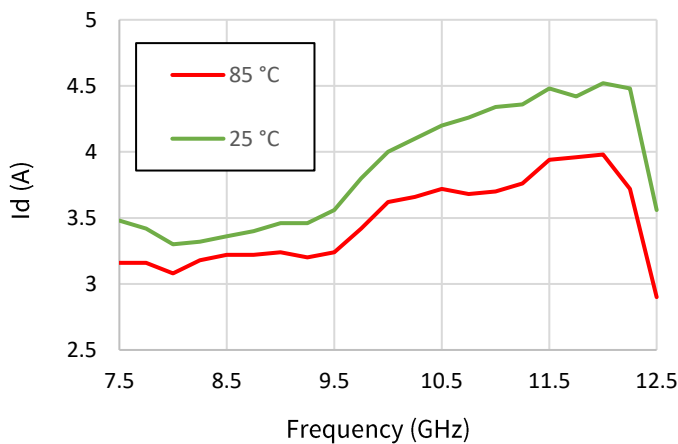


Figure 6: Ig v. Frequency v. Temperature

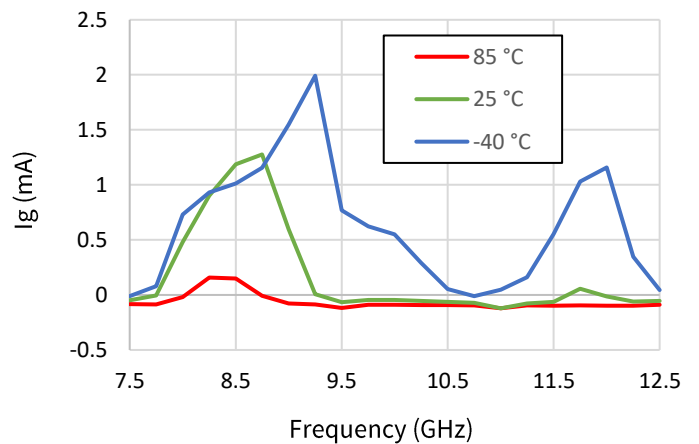
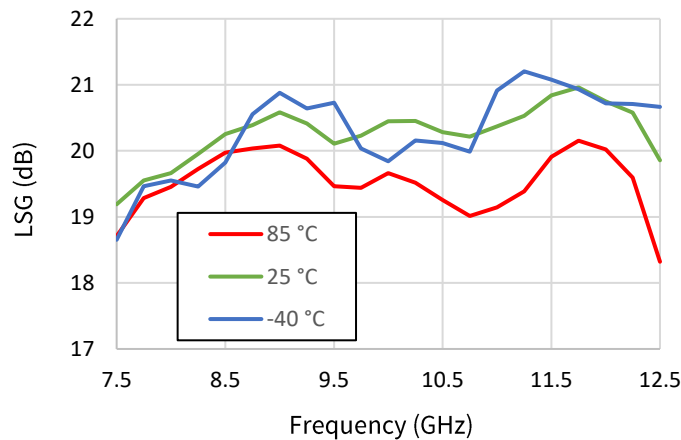


Figure 7: LSG v. Frequency v. Temperature



Test conditions unless otherwise noted: Vd=28V, Idq= 800mA, PW=100uS, DC=10%, Pin = 26dBm, T_{base}=25°C, Frequency =9.5 GHz

Figure 8: Pout v. Frequency v. Vd

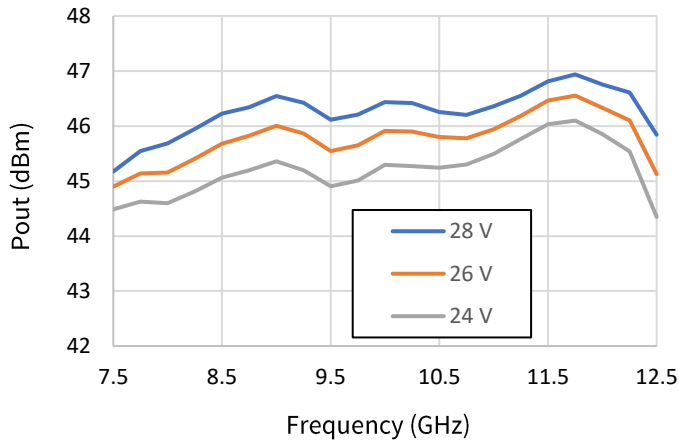


Figure 9: PAE v. Frequency v. Vd

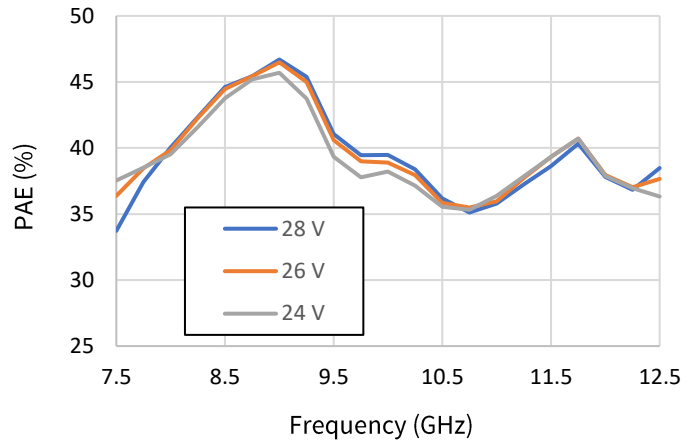


Figure 10: Id v. Frequency v. Vd

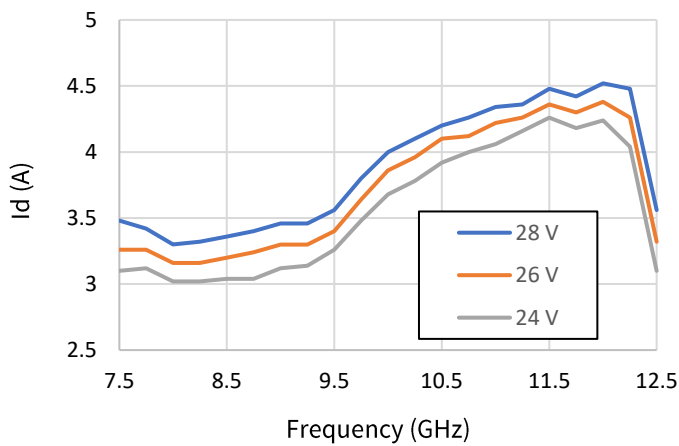


Figure 11: Ig v. Frequency v. Vd

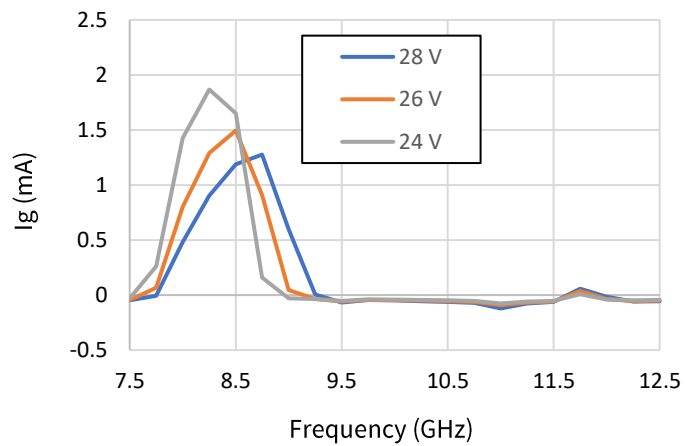
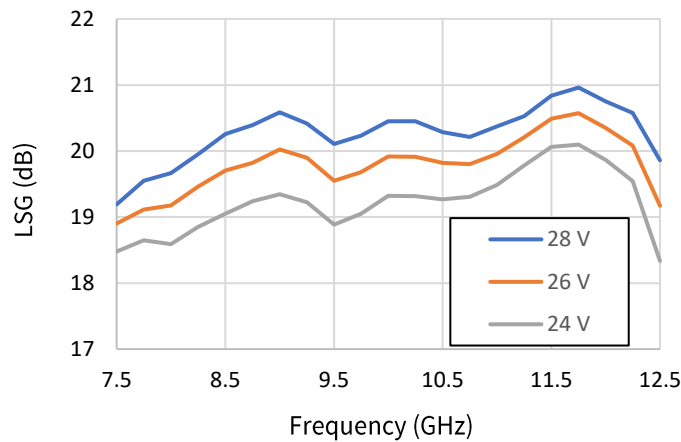


Figure 12: LSG v. Frequency v. Vd



Test conditions unless otherwise noted: $V_d=28V$, $I_{dq}=800mA$, $PW=100\mu s$, $DC=10\%$, $P_{in}=26dBm$, $T_{base}=25^\circ C$, Frequency =9.5 GHz

Figure 13: Pout v. Frequency v. Idq

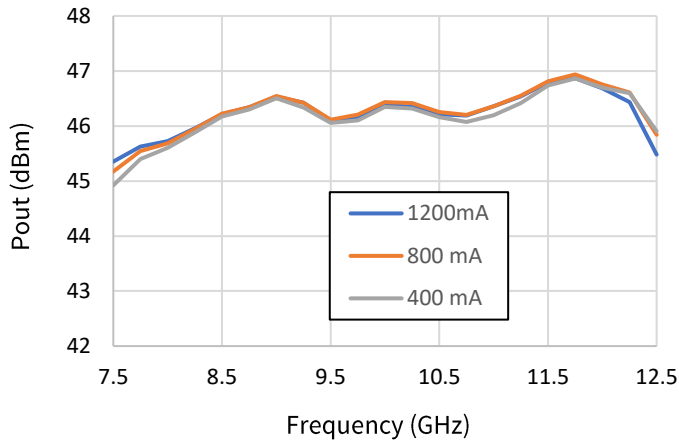


Figure 14: PAE v. Frequency v. Idq

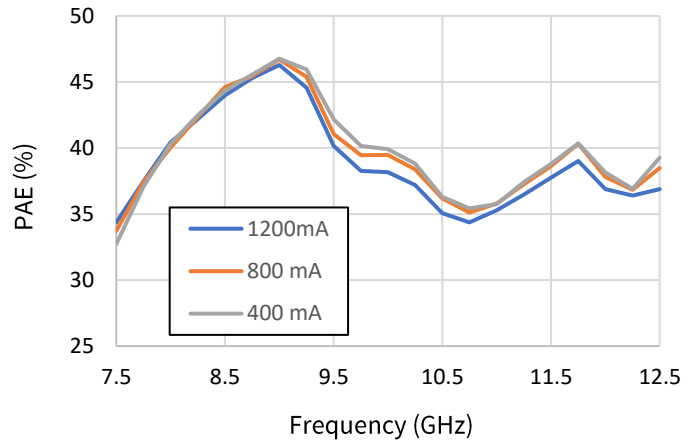


Figure 15: Id v. Frequency v. Idq

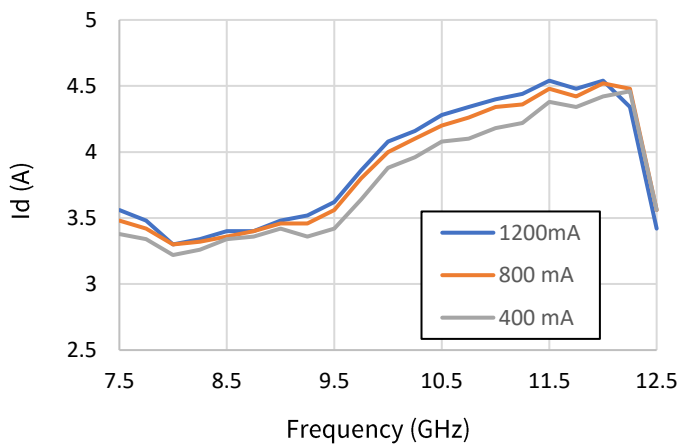


Figure 16: Ig v. Frequency v. Idq

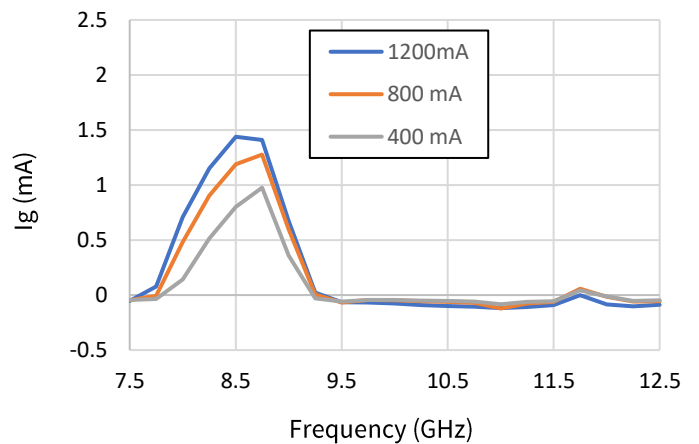
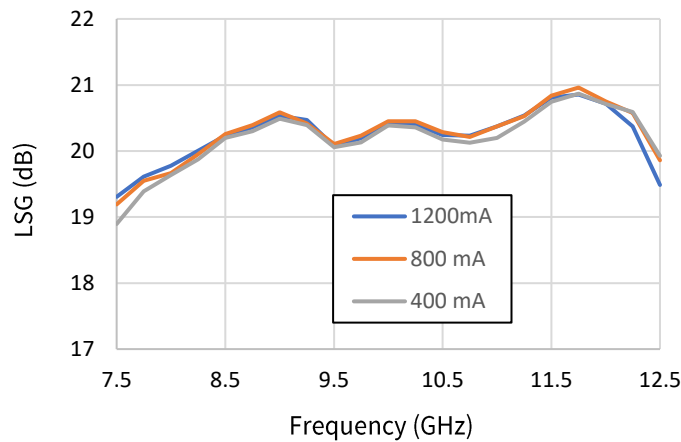


Figure 17: LSG v. Frequency v. Idq



Test conditions unless otherwise noted: $V_d=28V$, $I_{dq}=800mA$, $PW=100\mu S$, $DC=10\%$, $P_{in}=26dBm$, $T_{base}=25^\circ C$, Frequency =9.5 GHz

Figure 18: Pout v. Pin v. Frequency

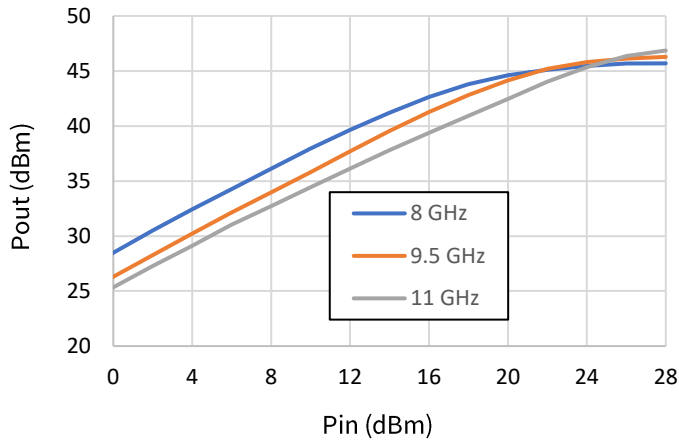


Figure 19: PAE v. Pin v. Frequency

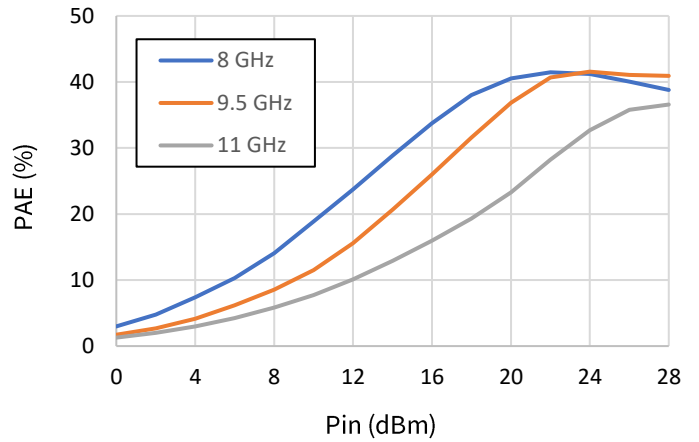


Figure 20: Id v. Pin v. Frequency

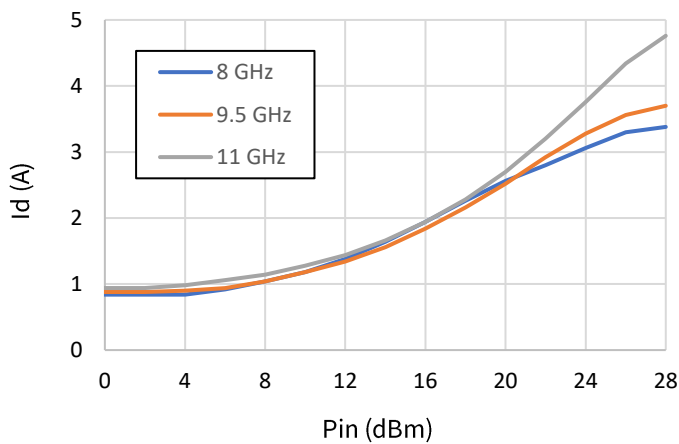


Figure 21: Ig v. Pin v. Frequency

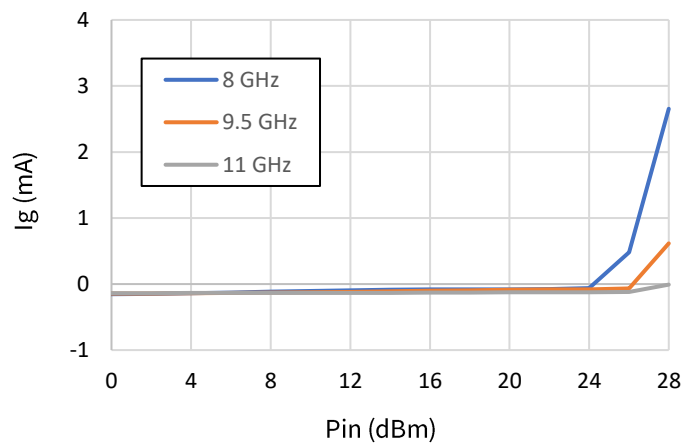
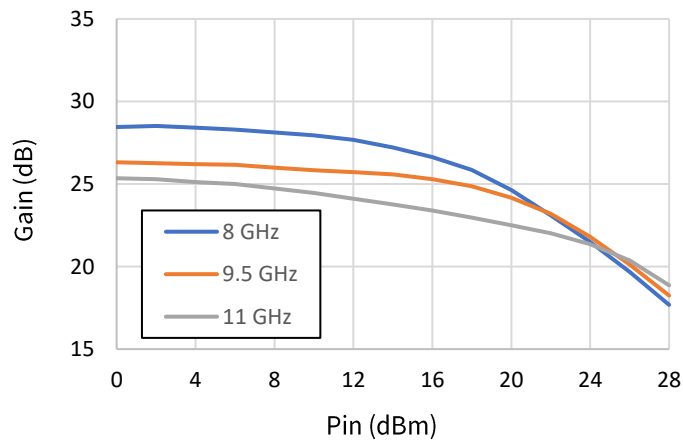


Figure 22: Gain v. Pin v. Frequency



Test conditions unless otherwise noted: $V_d=28V$, $I_{dq}=800mA$, $PW=100\mu S$, $DC=10\%$, $P_{in}=26dBm$, $T_{base}=25^\circ C$, Frequency =9.5 GHz

Figure 23: Pout v. Pin v. Temperature

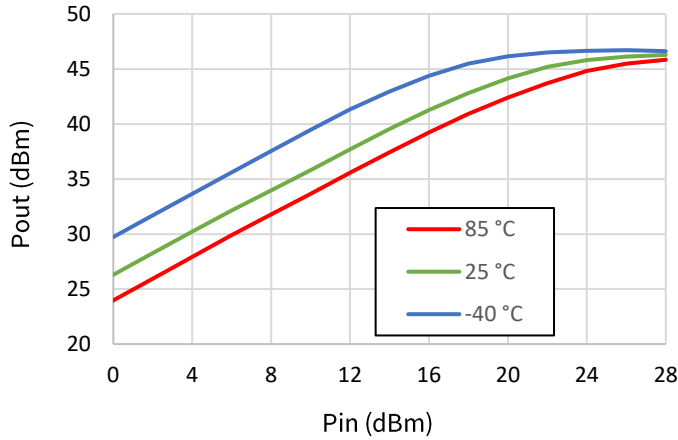


Figure 24: PAE v. Pin v. Temperature

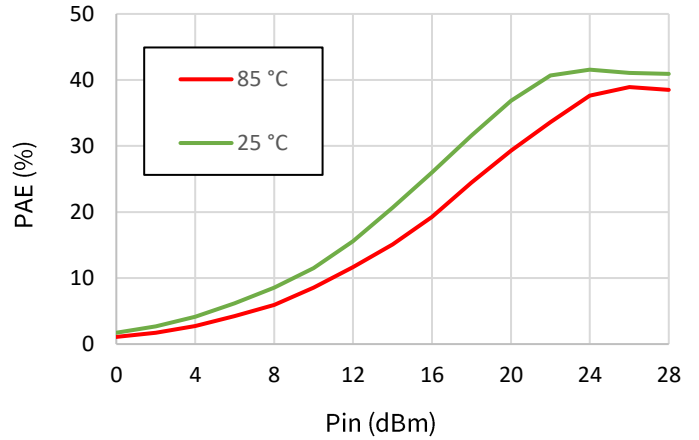


Figure 25: Id v. Pin v. Temperature

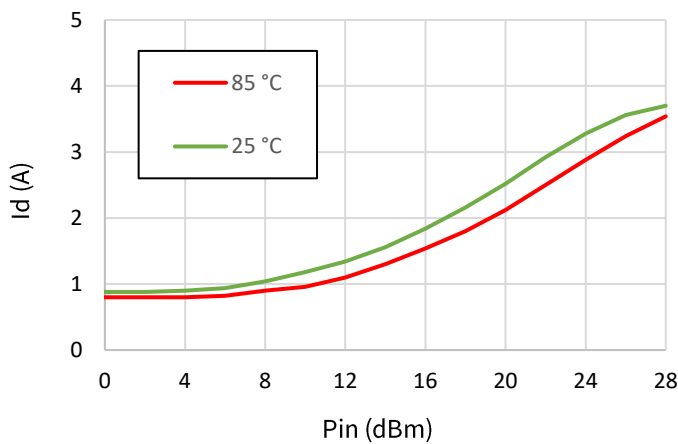


Figure 26: Ig v. Pin v. Temperature

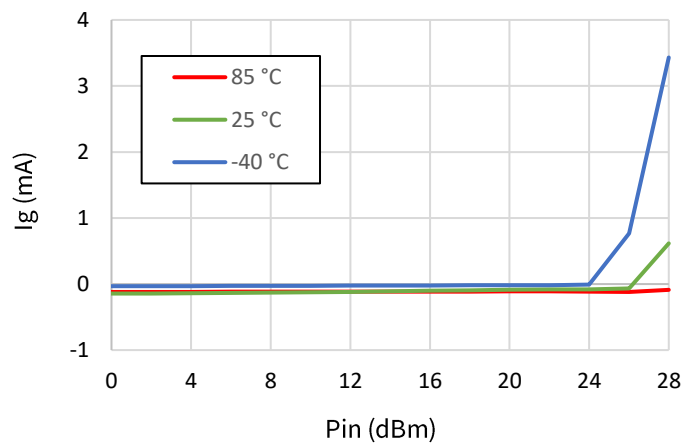
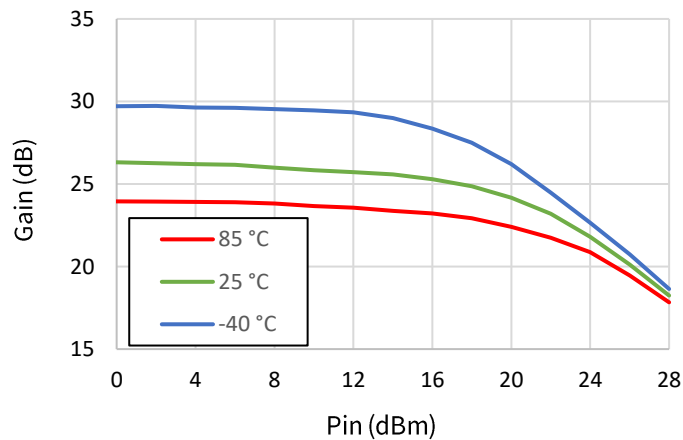


Figure 27: Gain v. Pin v. Temperature



Test conditions unless otherwise noted: Vd=28V, Idq= 800mA, PW=100uS, DC=10%, Pin = 26dBm, T_{base}=25°C, Frequency =9.5 GHz

Figure 28: Pout v. Pin v. Vd

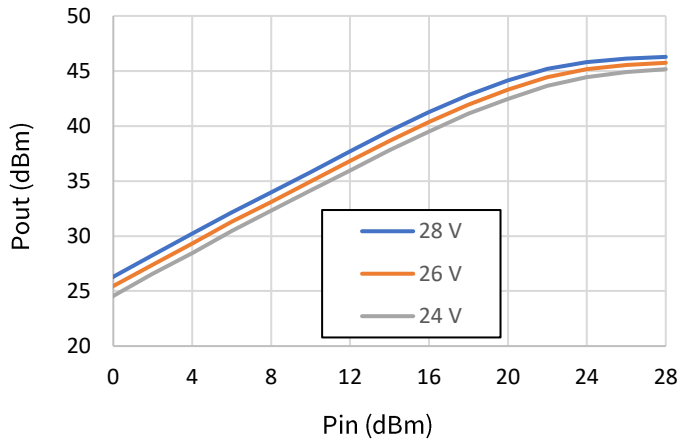


Figure 29: PAE v. Pin v. Vd

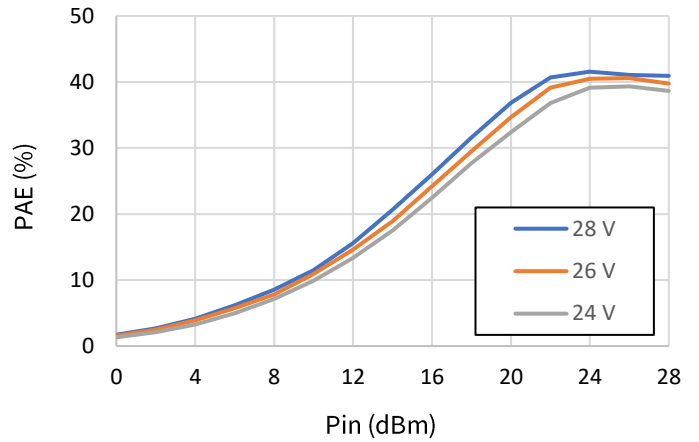


Figure 30: Id v. Pin v. Vd

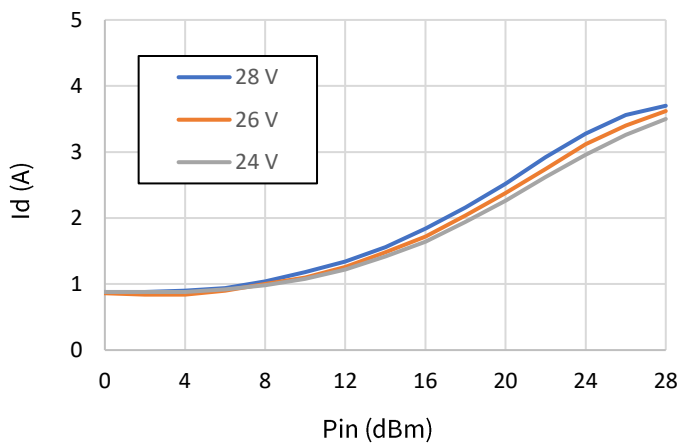


Figure 31: Ig v. Pin v. Vd

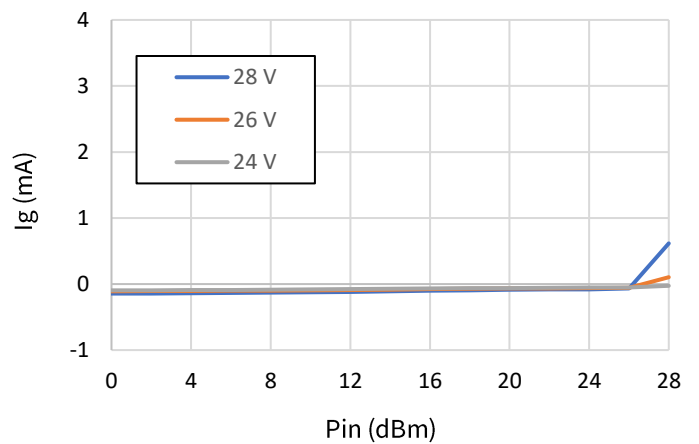
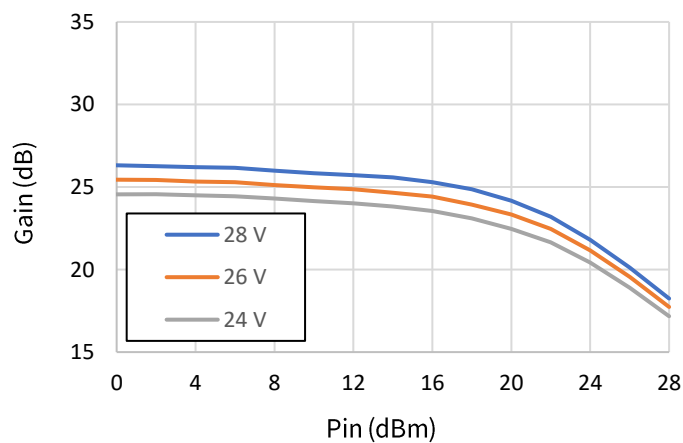


Figure 32: Gain v. Pin v. Vd



Test conditions unless otherwise noted: $V_d=28V$, $I_{dq}=800mA$, $PW=100\mu S$, $DC=10\%$, $P_{in}=26dBm$, $T_{base}=25^\circ C$, Frequency =9.5 GHz

Figure 33: Pout v. Pin v. Idq

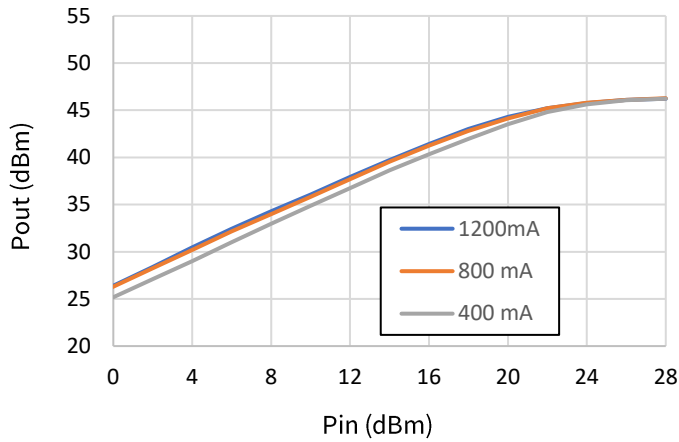


Figure 34: PAE v. Pin v. Idq

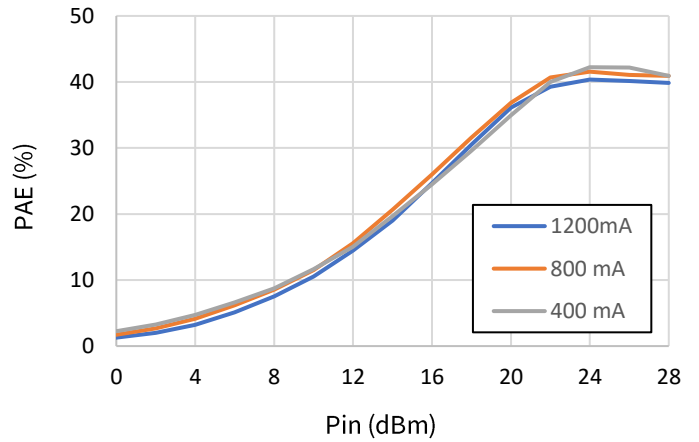


Figure 35: Id v. Pin v. Idq

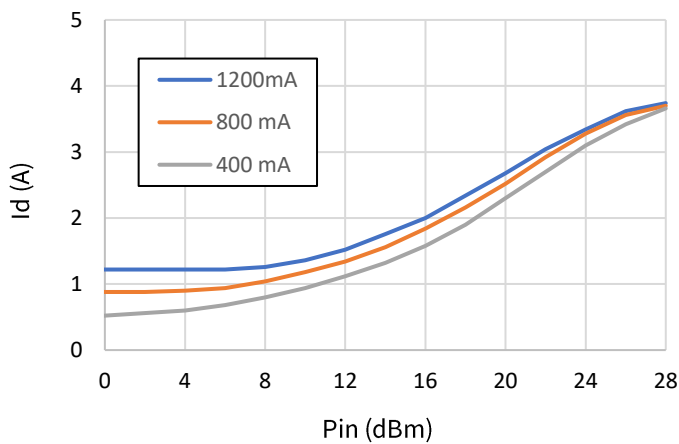


Figure 36: Ig v. Pin v. Idq

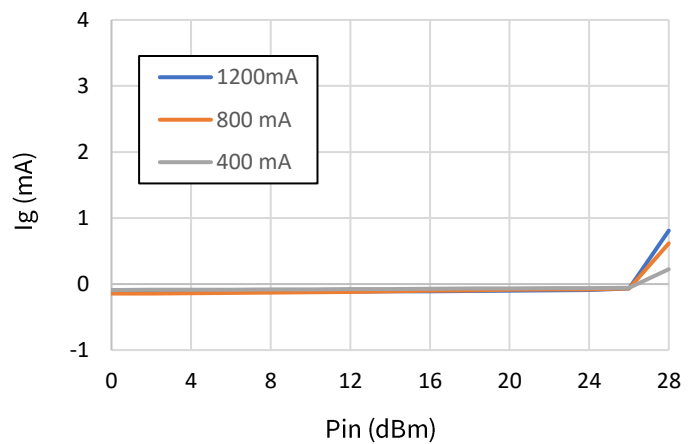
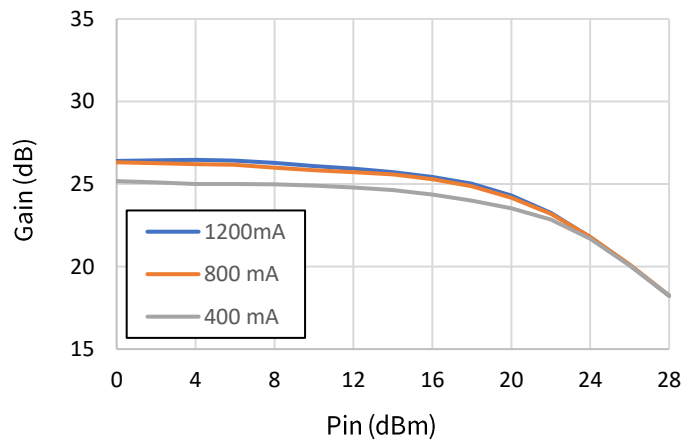


Figure 37: Gain v. Pin v. Idq



Test conditions unless otherwise noted: Vd=28V, Idq= 800mA, Pin = -20Bm, T_{base}=25°C

Figure 38: S21 v. Frequency v. Temperature

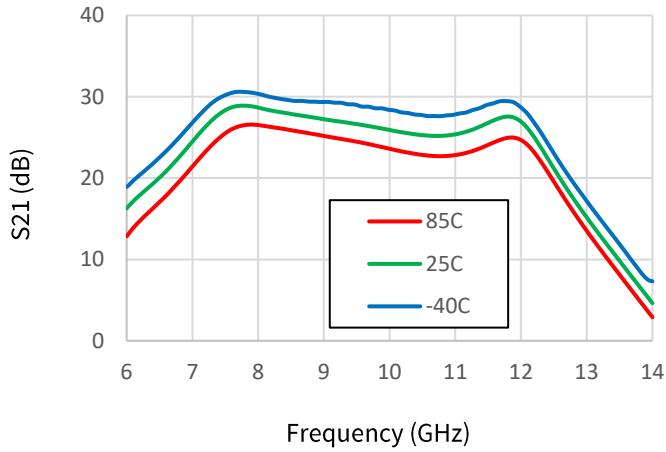


Figure 39: S21 v. Frequency v. Vd

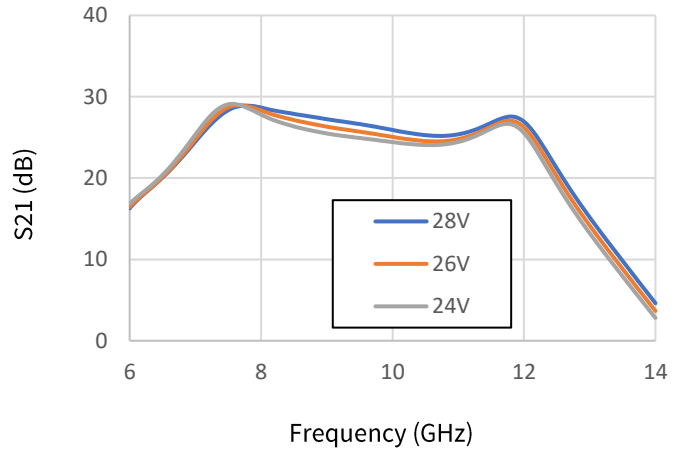


Figure 40: S11 v. Frequency v. Temperature

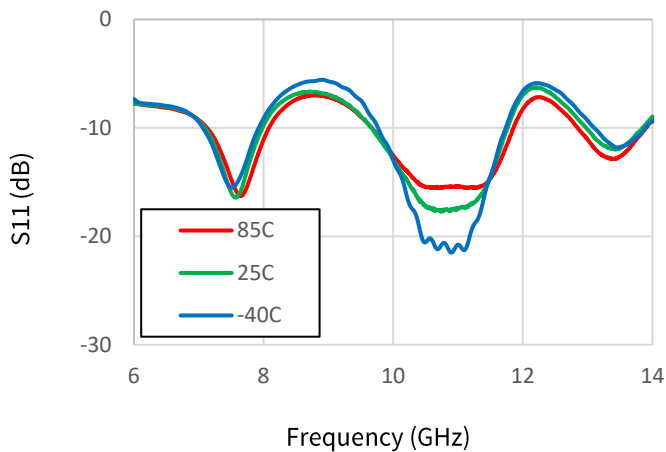


Figure 41: S11 v. Frequency v. Vd

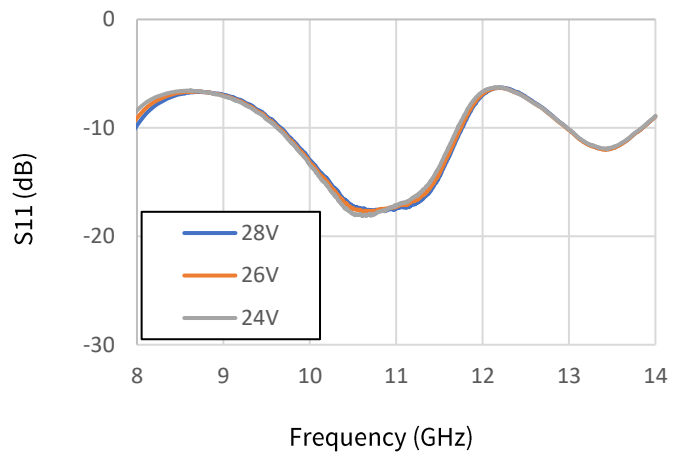


Figure 42: S22 v. Frequency v. Temperature

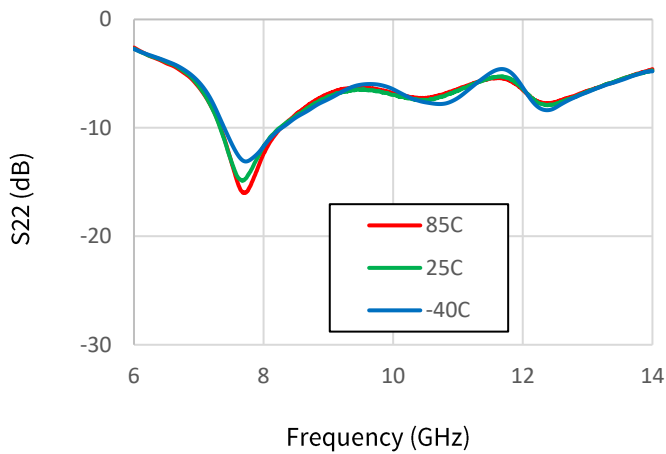
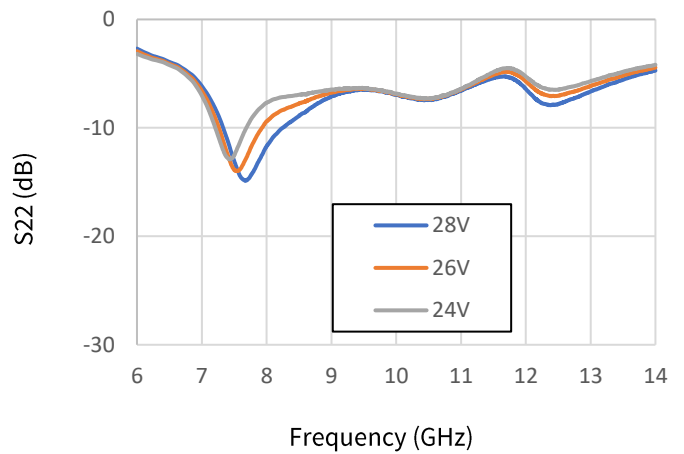


Figure 43: S22 v. Frequency v. Vd



Test conditions unless otherwise noted: $V_d=28V$, $I_{dq}=800mA$, $P_{in} = -20Bm$, $T_{base}=25^{\circ}C$

Figure 44: S21 v. Frequency v. Idq

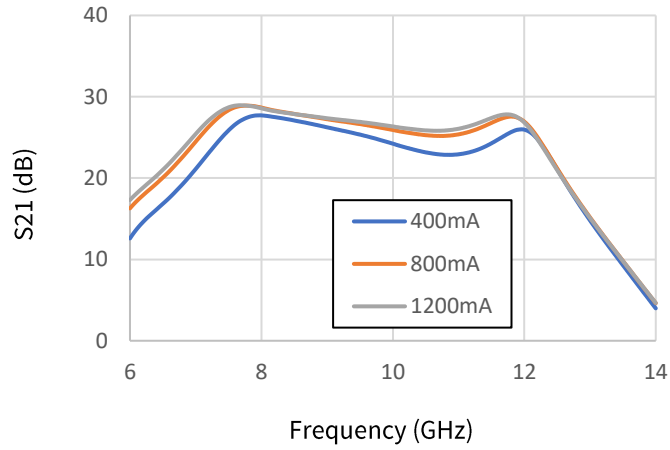


Figure 45: S11 v. Frequency v. Idq

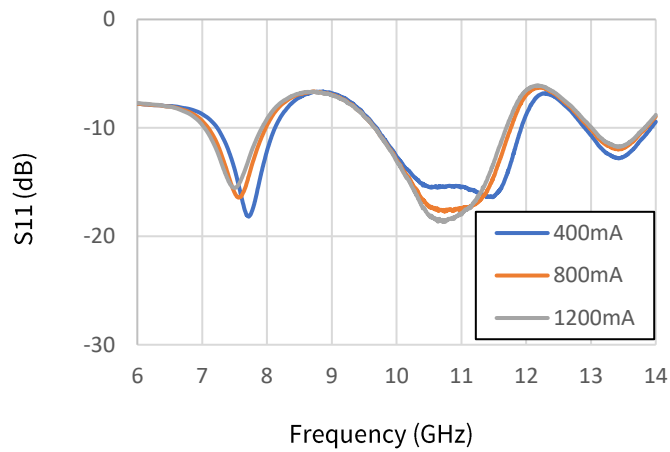
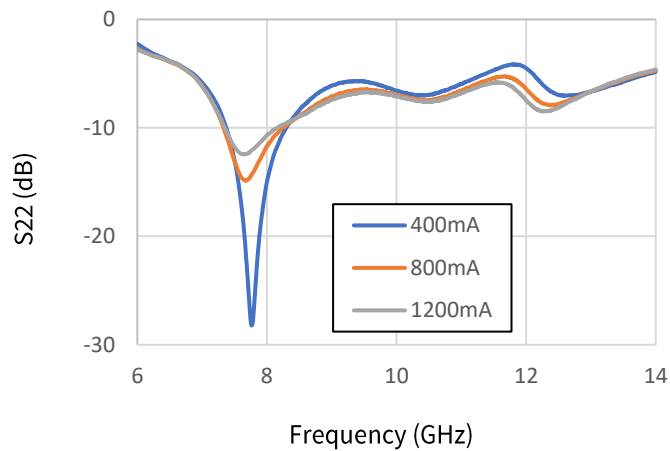


Figure 46: S22 v. Frequency v. Idq



Test conditions unless otherwise noted: $V_d=28V$, $I_{dq}=800mA$, $PW=100\mu S$, $DC=10\%$, $P_{in}=26dBm$, $T_{base}=25^\circ C$

Figure 53: 2f v. Pout v. Temperature, 8 GHz

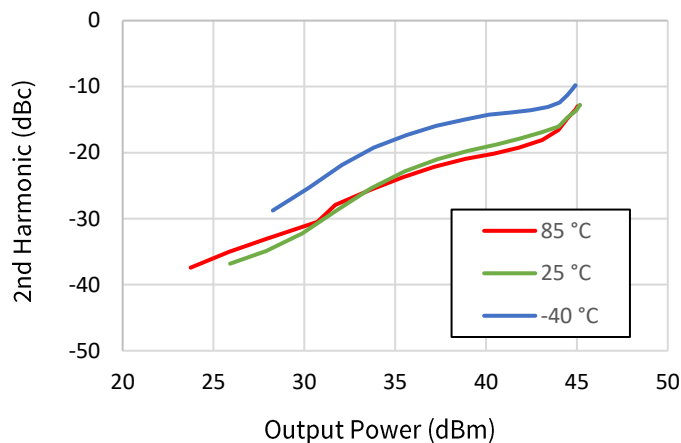


Figure 54: 2f v. Pout v. Vd, 8 GHz

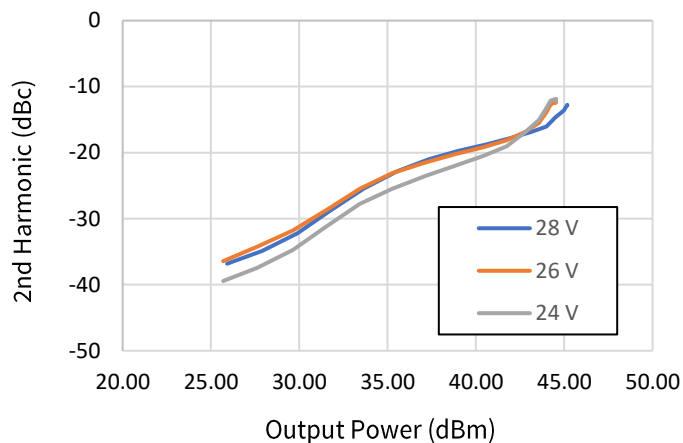


Figure 55: 2f v. Pout v. Temperature, 9.5 GHz

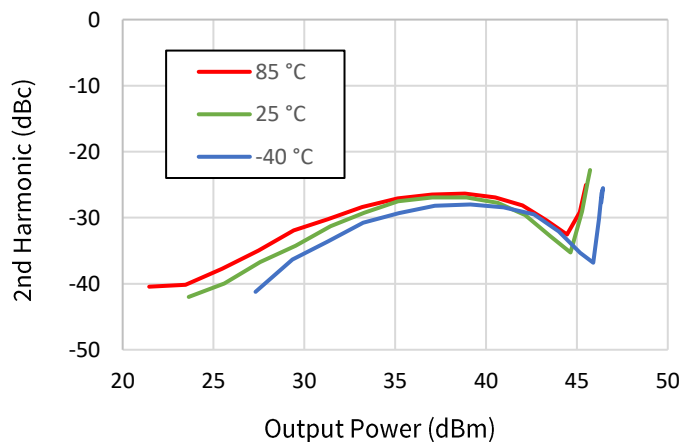


Figure 56: 2f v. Pout v. Vd, 9.5 GHz

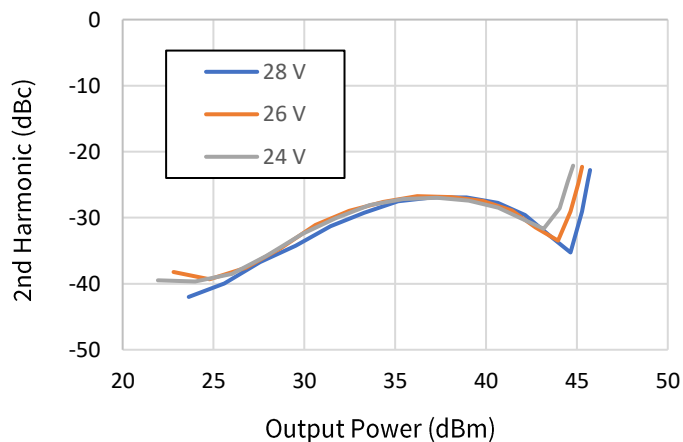


Figure 57: 2f v. Pout v. Temperature, 11 GHz

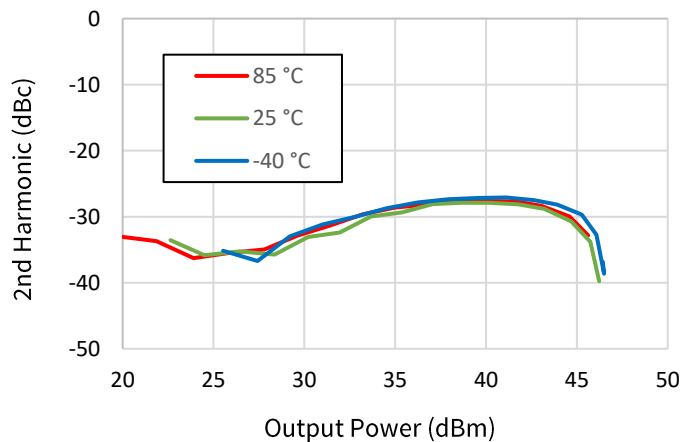
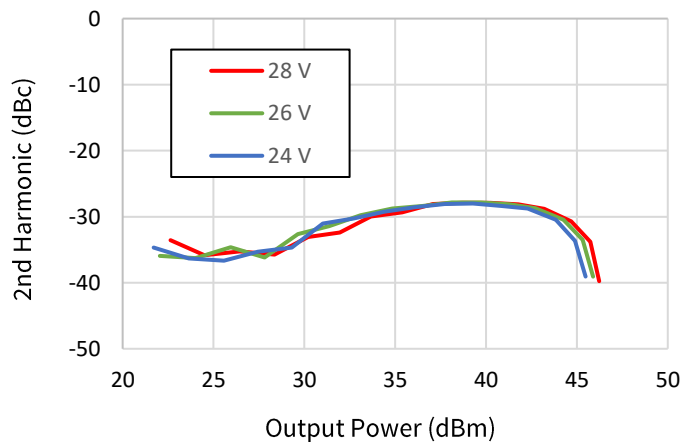


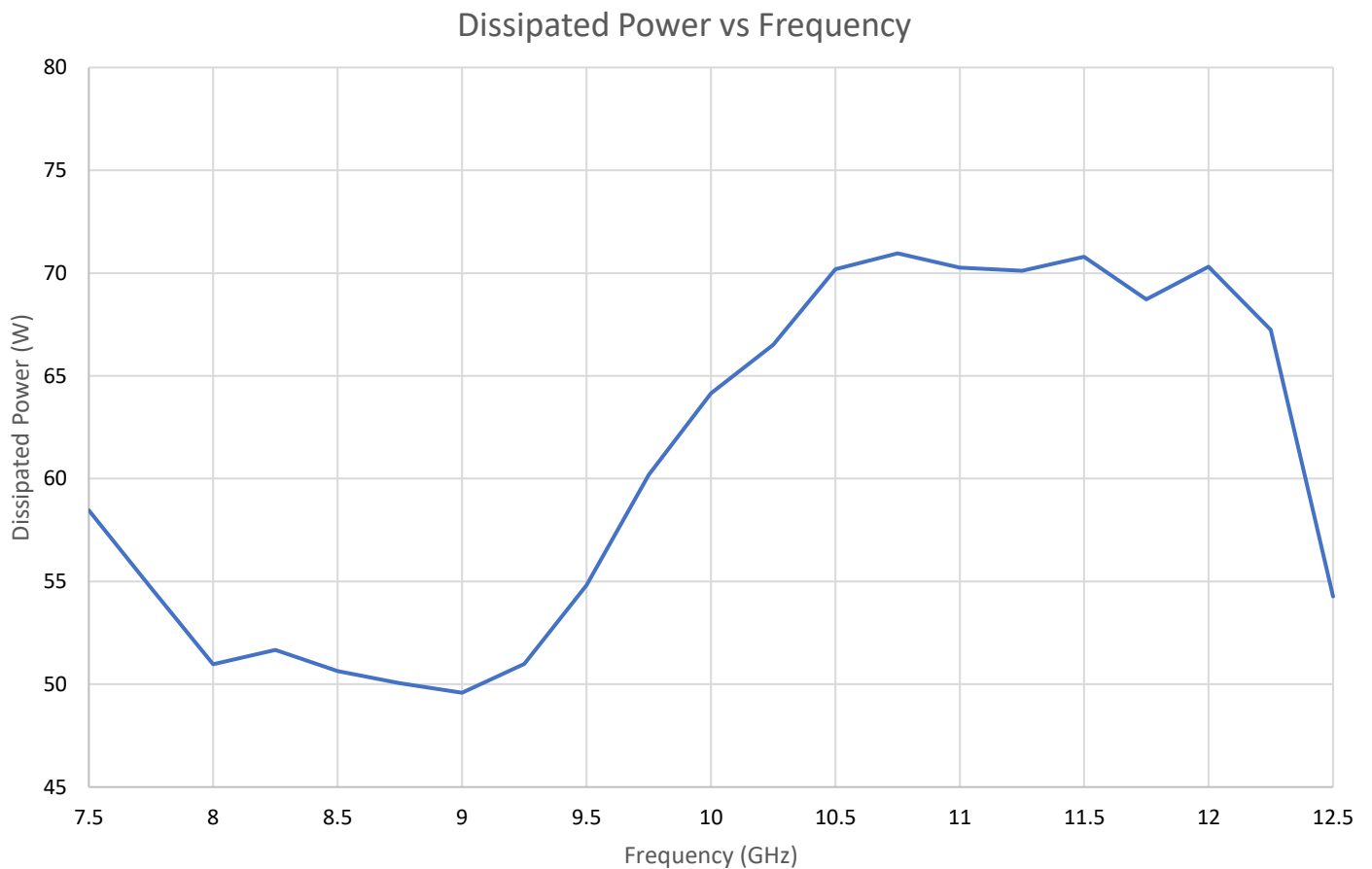
Figure 58: 2f v. Pout v. Vd, 11 GHz



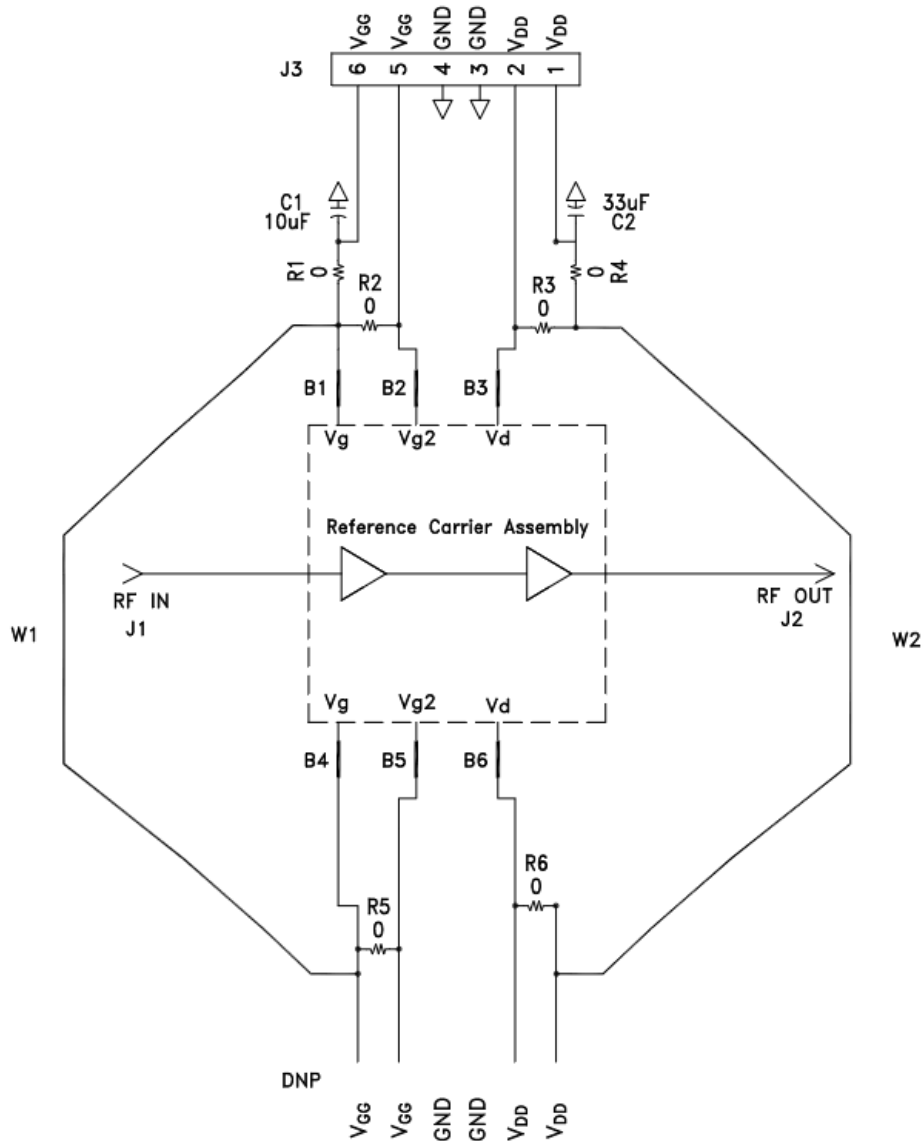
Thermal Characteristics

Parameter	Symbol	Value	Operating Conditions
Operating Junction Temperature	T_J	186 °C	Pulse Width = 100uS, Duty Cycle = 10%, $P_{Diss} = 71W$, $T_{base} = 85^\circ C$
Thermal Resistance, Junction to Back of Die	$R_{\theta JC}$	1.42 °C/W	

Power Dissipation v. Frequency (Tcase = 85C)



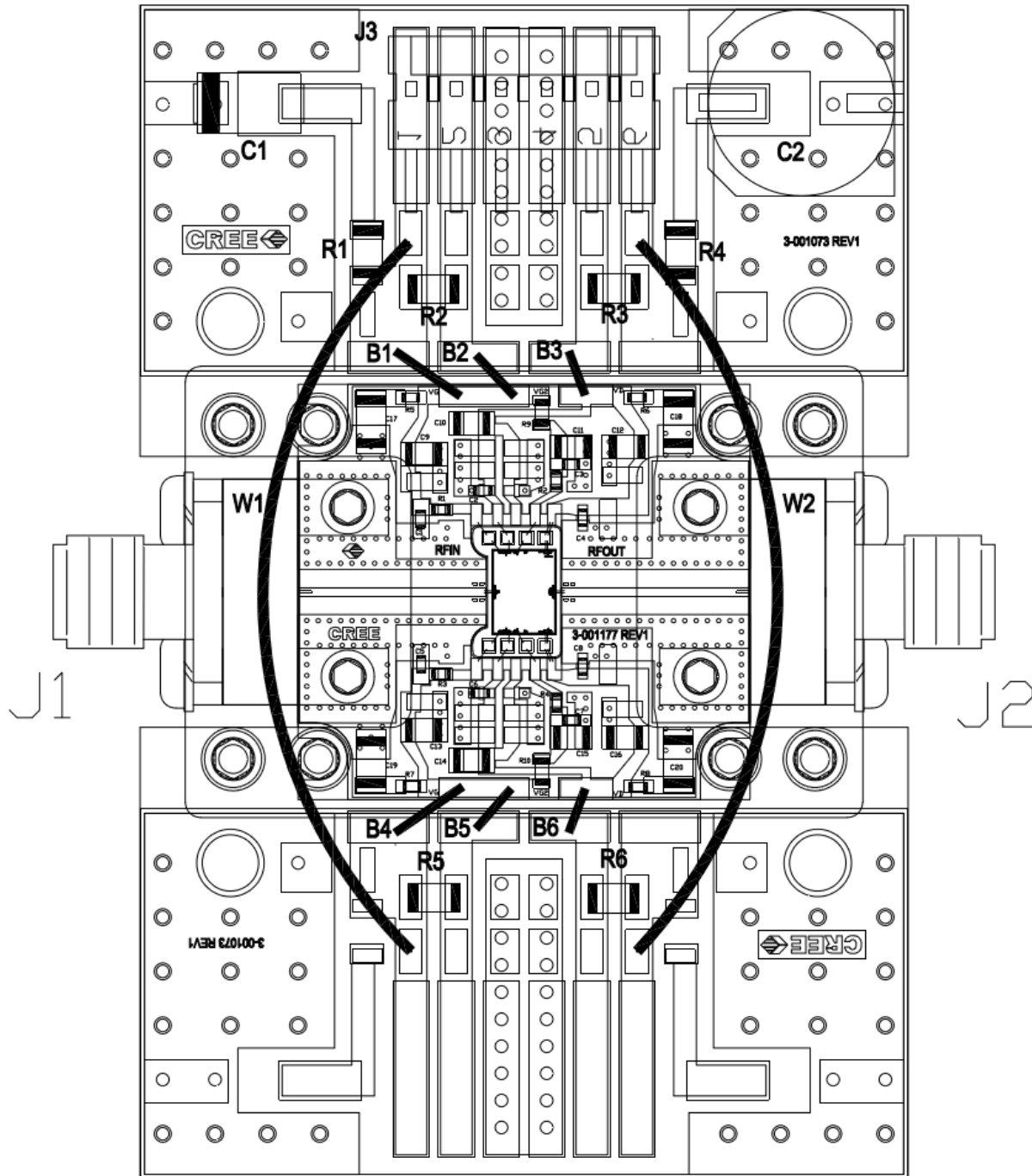
CMPA801B030D1-AMP Evaluation Board Schematic Drawing



CMPA801B030D1-AMP Evaluation Board Bill of Materials

Reference Designator	Description	Qty
J1, J2	CONNECTOR SMA JACK (FEMALE) END LAUNCH	2
J3	6-PIN DC HEADER, RIGHT ANGLE	1
R1-R6	RESISTOR, 0 OHMS, 1206	6
C1	CAPACITOR, 10UF, TANTALUM	1
C2	CAPACITOR, 33UF, ELECTROLYTIC	1
B1-B6	JUMPER WIRE	6
W1-W2	WIRE, BLACK, 22AWG (~2")	2

CMPA801B030D1-AMP Evaluation Board Assembly Drawing



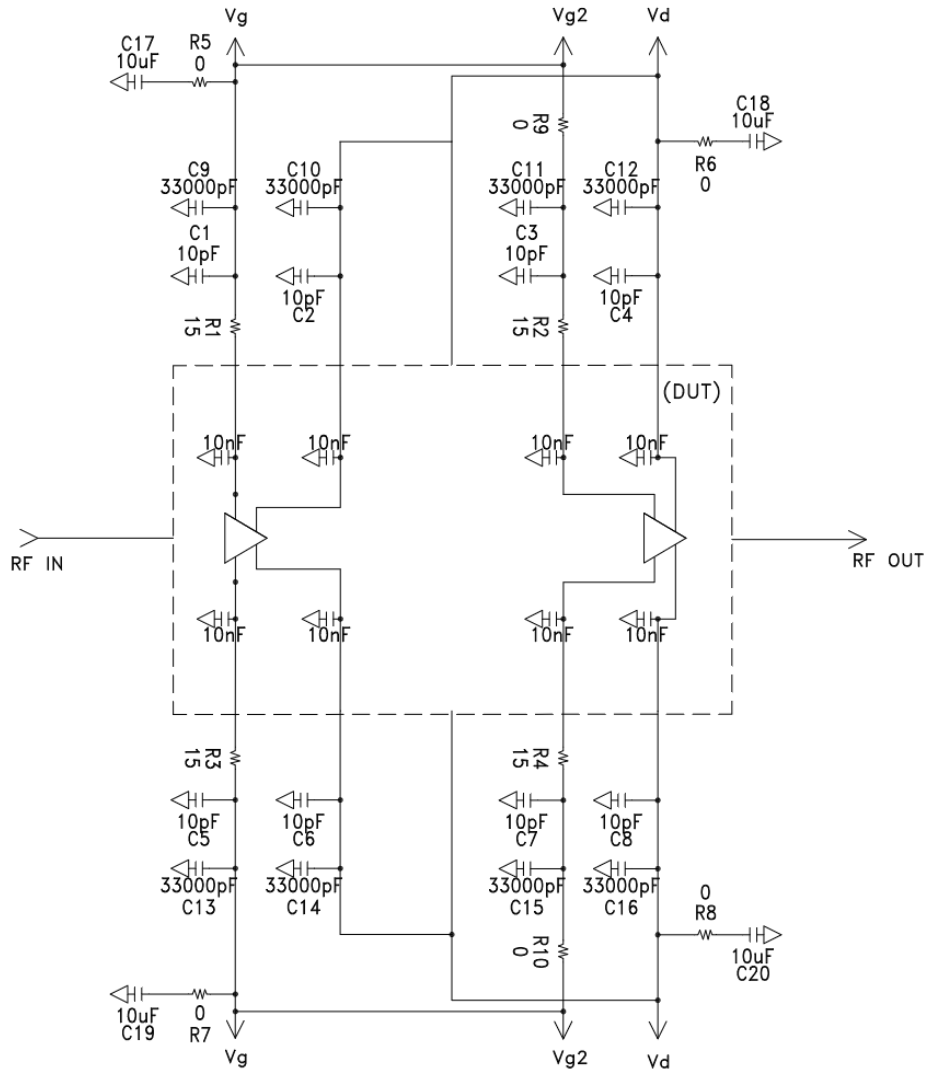
Bias On Sequence

1. Ensure RF is turned-off
2. Apply pinch-off voltage of -5 V to the gate (V_g)
3. Apply nominal drain voltage (V_d)
4. Adjust V_g to obtain desired quiescent drain current (I_{dq})
5. Apply RF

Bias Off Sequence

1. Turn RF off
2. Apply pinch-off to the gate ($V_g=-5V$)
3. Turn off drain voltage (V_d)
4. Turn off gate voltage (V_g)

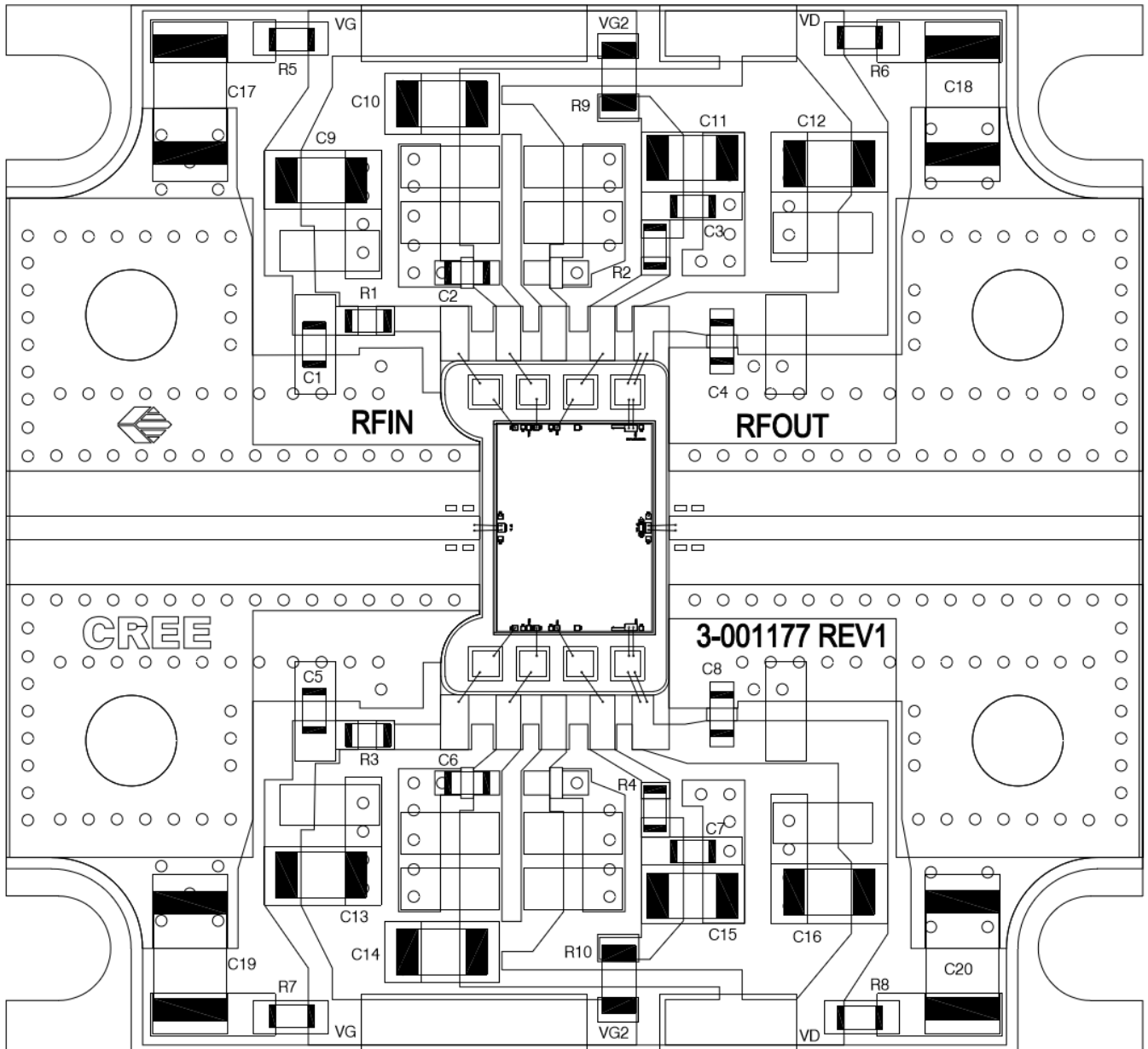
CMPA801B030D1-AMP Carrier Schematic Drawing



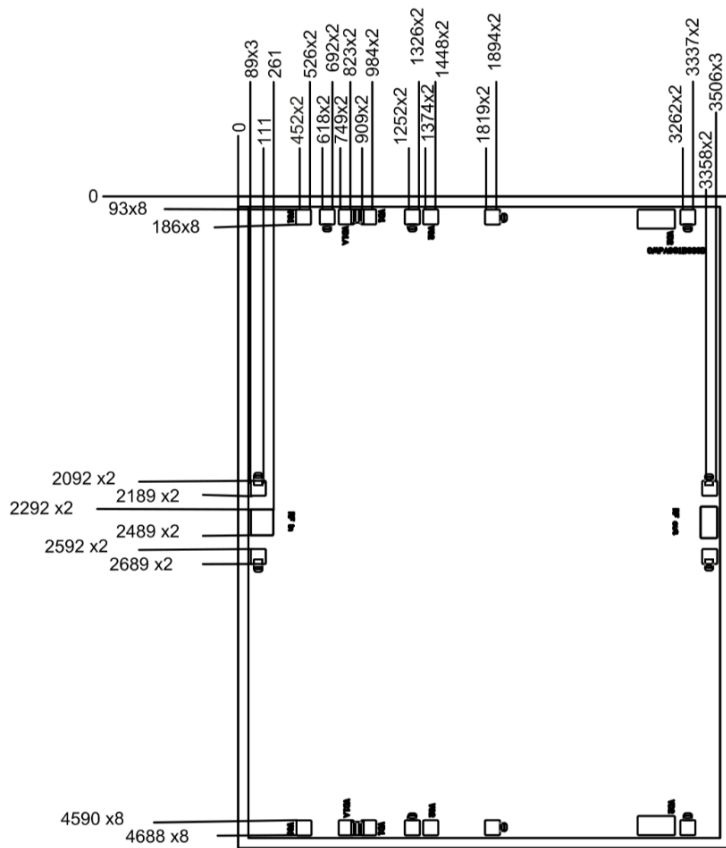
CMPA801B030D1-AMP Carrier Bill of Materials

Reference Designator	Description	Qty
R1 – R4	RESISTOR, 0402, 15 Ohms	4
R5 – R8	RESISTOR, 0402, 0 Ohms	4
R9, R10	RESISTOR, 0603, 0 Ohms	2
C1 – C8	CAPACITOR, 10 pF, 5%, 0402, ATC	8
C9 – C16	CAPACITOR, 33000 pF, 0805, X7R	8
C17 – C20	CAPACITOR, 10 uF, 1206	4

CMPA801B030D1-AMP Carrier Assembly Drawing



Product Dimensions



Overall die size 4780 x 3610 (+0/-50) microns, die thickness 100 (+/-10) micron.
 All Gate and Drain pads must be wire bonded for electrical connection.

Pad	Function	Description	Pad Size (microns)	Note
1	RF-IN	RF-Input pad. Matched to 50 ohm.	190 x 165	4
2	VG1_A	Gate control for stage 1. $V_G \sim 2.0 - 3.5$ V.	110 x 110	1,2
3	VG1_B	Gate control for stage 1. $V_G \sim 2.0 - 3.5$ V.	110 x 110	1,2
4	VD1_A	Drain supply for stage 1. $V_D = 28$ V.	110 x 110	1
5	VD1_B	Drain supply for stage 1. $V_D = 28$ V.	110 x 110	1
6	VG2_A	Gate control for stage 2A. $V_G \sim 2.0 - 3.5$ V.	110 x 110	1,3
7	VG2_B	Gate control for stage 2A. $V_G \sim 2.0 - 3.5$ V.	110 x 110	1,3
8	VD2_A	Drain supply for stage 2A. $V_D = 28$ V.	274 x 140	1
9	VD2_B	Drain supply for stage 2B. $V_D = 28$ V.	274 x 140	1
10	RF-Out	RF-Output pad. Matched to 50 ohm.	150 x 150	4

Note 1: Attach bypass capacitor to pads 2-9 per application circuit

Note 2: VG1_A and VG1_B are connected internally so it would be enough to connect either one for proper operation

Note 3: VG2_A and VG2_B are connected internally so it would be enough to connect either one for proper operation

Note 4: The RF Input and Output pad have a ground-signal-ground with a nominal pitch of 1 mil (25 um). The RF ground pads are 110 x 110 microns

Electrostatic Discharge (ESD) Classification

Parameter	Symbol	Class	Test Methodology
Human body Model	HBM	TBD	JEDEC JESD22 A114-D
Charge Device Model	CDM	TBD	JEDEC JESD22 C101-C